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FOREIGN PATENT DOCUMENTS									
		DOCUMENT NUMBER	DATE	COUNTRY		YES	TRANSLATION YES NO		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
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*Examiner: In conformance	itial if r	*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							